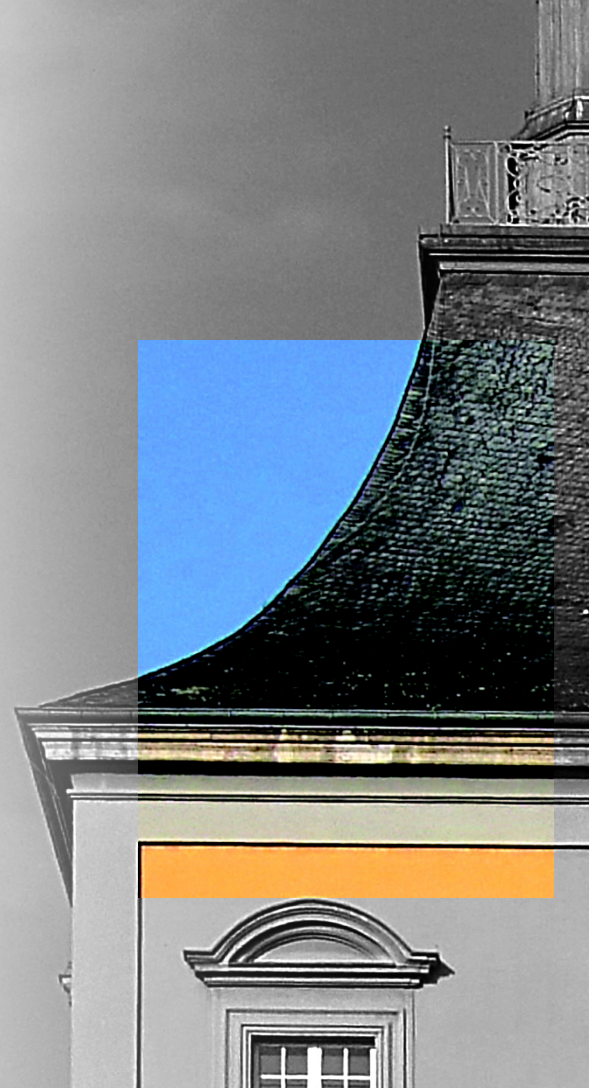


OPTIMISATION STRATEGY FOR THE SENSOR BASED ON THE MPW3 MONOLITHIC DETECTOR

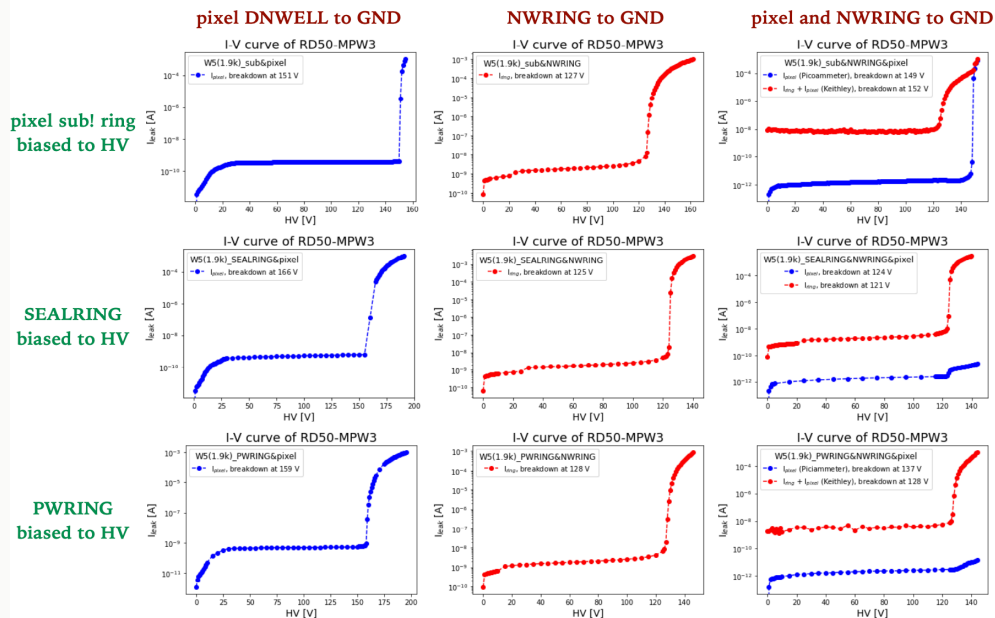
Preliminary and Conceptual Ideas

Sinuo Zhang
30.03.2023



MEASUREMENTS OF THE BREAKDOWN VOLTAGE IN LIVERPOOL

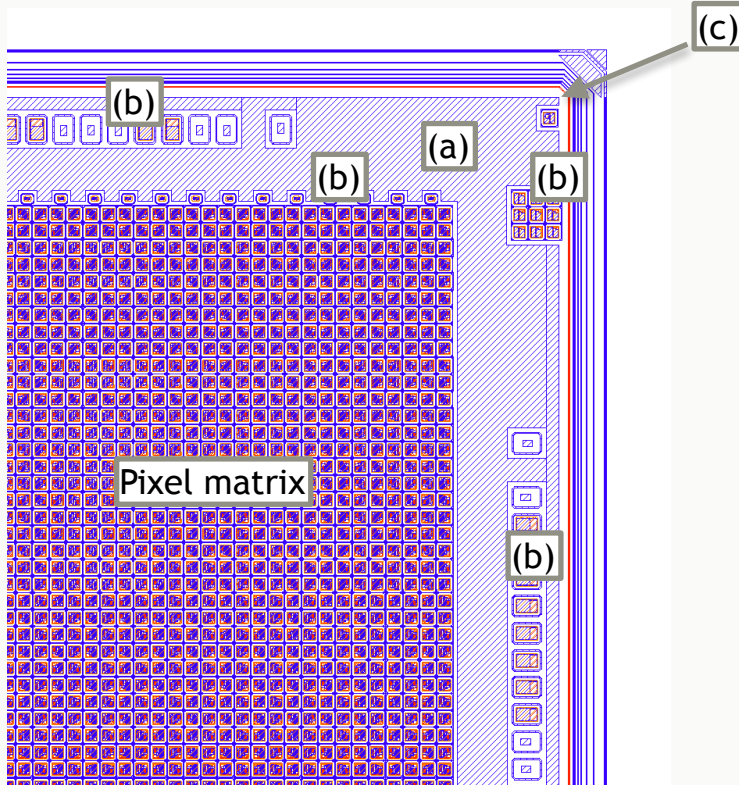
RD50-MPW3 initial IV measurements



RD50 CMOS meeting (2022.09.15) - Chenfan Zhang

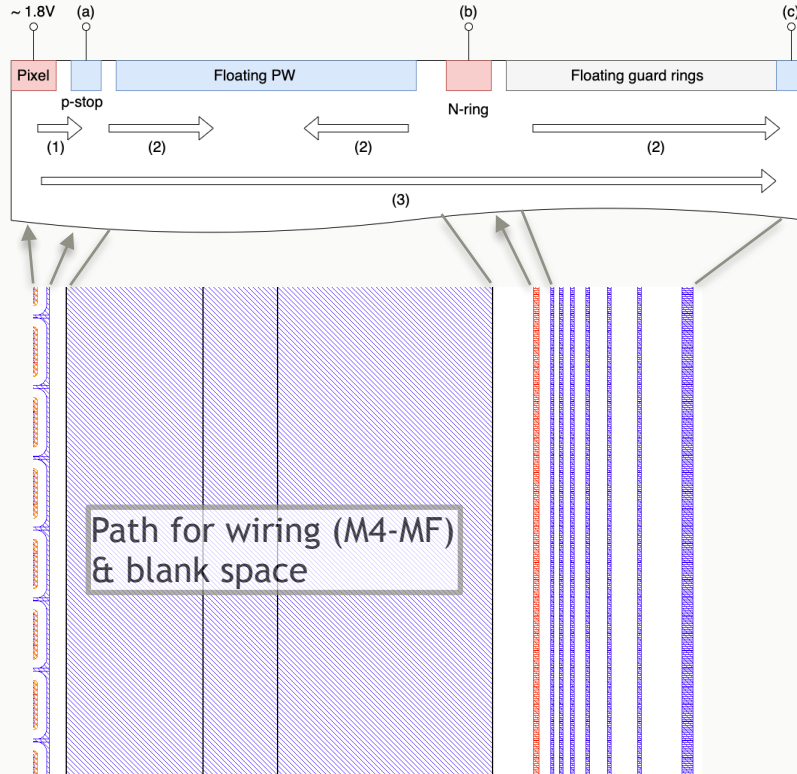
- Measurements of almost all scenarios showing:
 - Large current increase at bias voltage between 120 V and 150V
- Breakdown possibly takes place between the p-stop and pixel (distance of 8um)
- Nevertheless, still hard to locate where the breakdown actually takes place
 - May locate at the implants with similar spacing of 8um

OBSERVATIONS FROM THE LAYOUT



- (a): large floating PW between pixel matrix and GR
 - Directly encloses the pixel matrix
 - Width is not uniform
- (b): isolated structures
 - Physically isolated from the pixel matrix
 - P-stop/ring connected together
 - Locations do not follow a pattern
 - Individual size and structure
- (c): sharp corners
 - Appears at various locations
- Etc. similar cases in the rest part of the chip
- If bias through p-stop -> potential drop more or less predictable
- If bias through edge/back (floating p-stop)
 - > hard to predict the potential distribution among implants

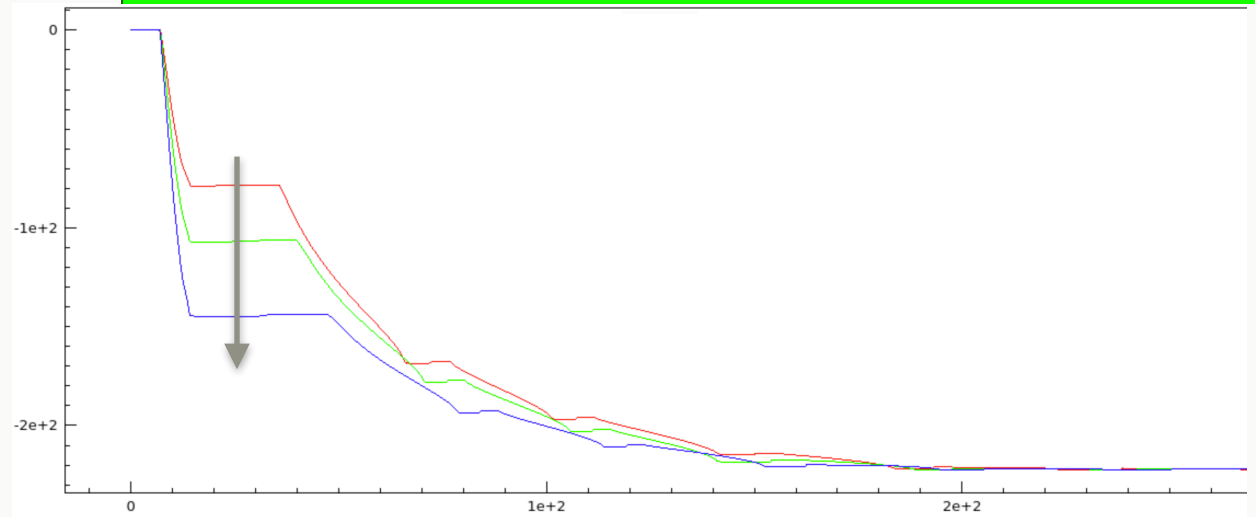
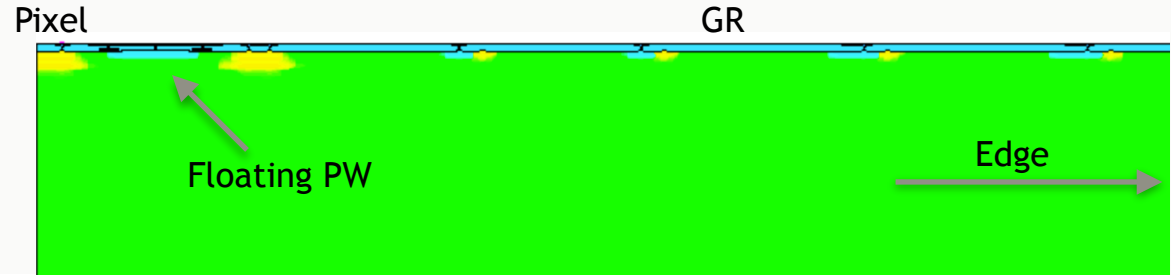
POTENTIAL FROM MATRIX TO THE EDGE



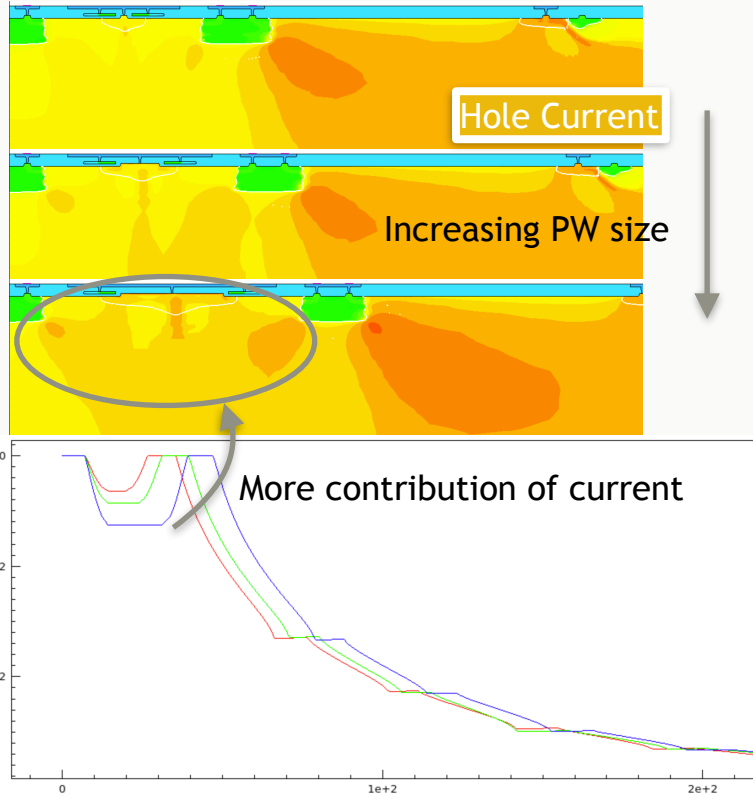
- (I) Current biasing method: - HV at (a)
 - Potential drop (1), the rest not really relevant
- (II) Edge bias (-HV at (c)) with floating p-stop:
 - Potential drop (3), across the entire periphery
 - Large floating PW suppresses the potential
 - Potential drop (1) dominates
- (III) Edge bias (-HV at (c)) with floating p-stop and biased N-ring (0V or ~1.8V at (b))
 - Potential drop (2), potential drop consists of two parts
 - Guard ring region determined by the geometry
 - Large floating PW + p-stop can cause large potential drop, although it should be less significant as the previous case

(II) EDGE BIAS (-HV AT (C)) WITH FLOATING P-STOP

- Not exactly the same structure for simulation, but the idea is the same
- Larger floating PW close to the pixel implant leads to lower potential
- Therefore smaller breakdown voltage



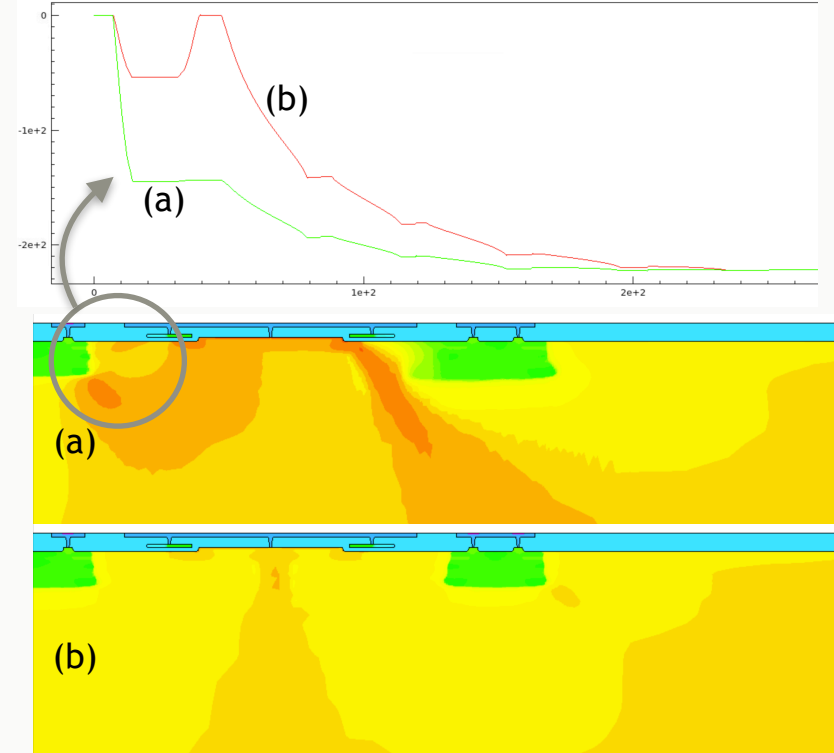
(II) EDGE BIAS (-HV AT (C)) WITH FLOATING P-STOP AND BIASED N-RING (0V OR $\sim 1.8\text{V}$ AT (B))



- The biased n-ring (at the same voltage as the pixel) holds the potential of the floating PW at a higher level
- Potential drop at the PW increases with larger width

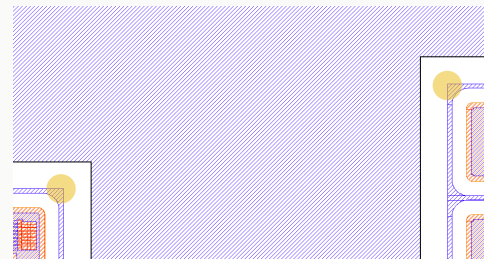
COMPARE BOTH CASES (II) & (III)

- Set the n-ring to a fixed voltage will significantly reduce the voltage drop at the same bias voltage
- Current contribution (from impact ionisation) is reduced



SUMMARY OF THOUGHTS

1. If we use edge bias, the guard ring structure may not be the only part requires optimisation
2. The large floating PW can cause a dominating potential drop
3. The structure like an n-ring can be very helpful to regulate the potential distribution

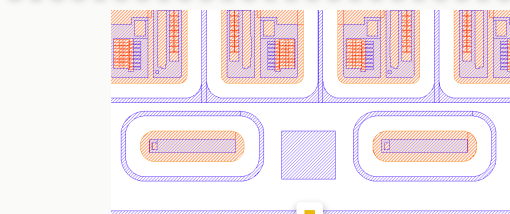
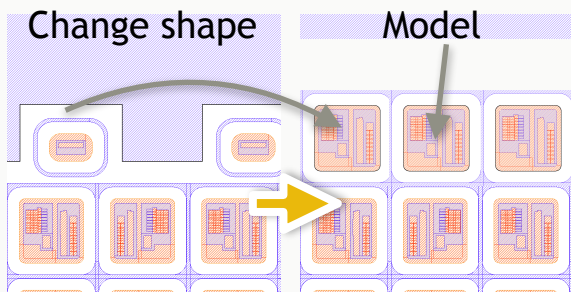


Measures

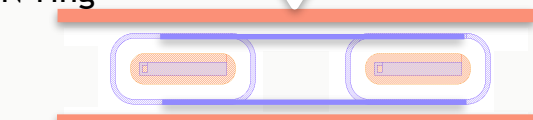
1. Round sharp corners ✓
 - ➔ Less possibility to have high field
2. Re-organise the isolated structures in the periphery
 - ➔ More ordered implant geometry
 - ➔ Easier to predict and debug (if necessary)
3. Reduce the size of the floating PW
 - ➔ Reduce potential drop
4. Implement N-ring/DNW
 - ➔ Regulate potential & field, provide shielding
5. Optimise guard ring

NAIVE EXAMPLES: RE-ORGANISE

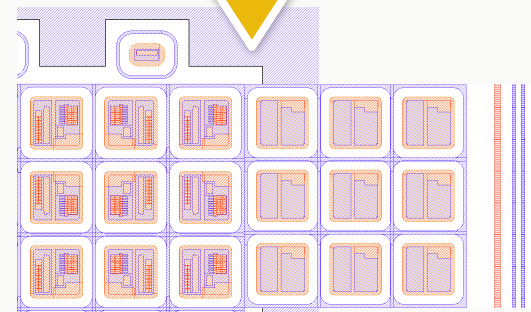
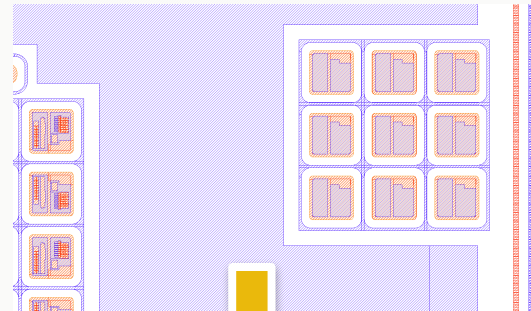
- For the structures having a “p-stop” with the same voltage as the matrix, we can merge the p-stop and integrate them into the matrix
- Can change the shape of certain structures besides the matrix and merge into the matrix. Can also use models which acts merely as a passive pixel
- For the structures hard to change, we can eliminate the floating PW and put in n-ring. Would be nice if they can be in a common DNW and be a part of the n-ring



N-ring



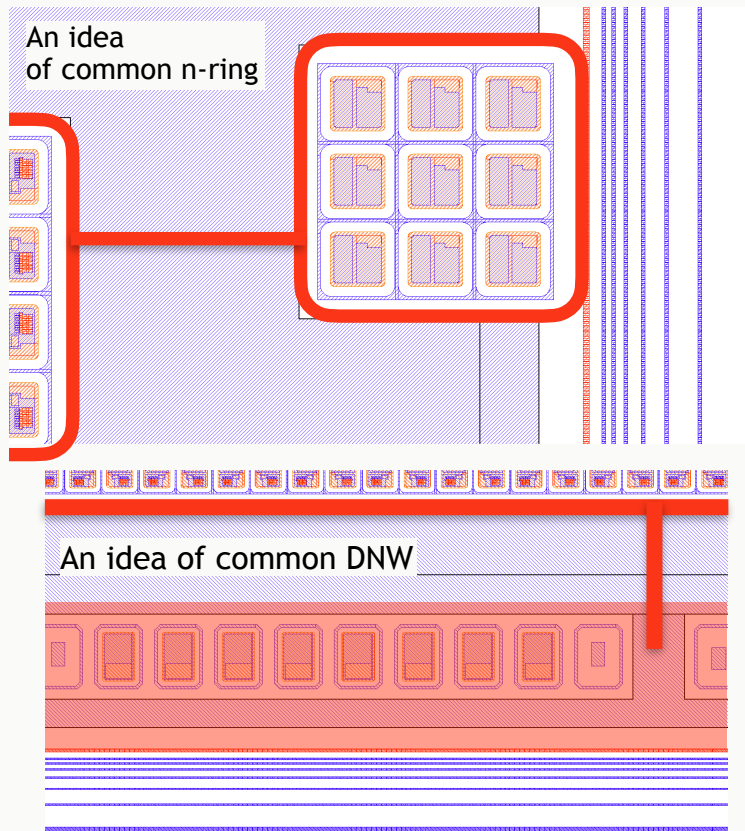
Possible to put these in a common DNW ?



A column of passive structures/models ...

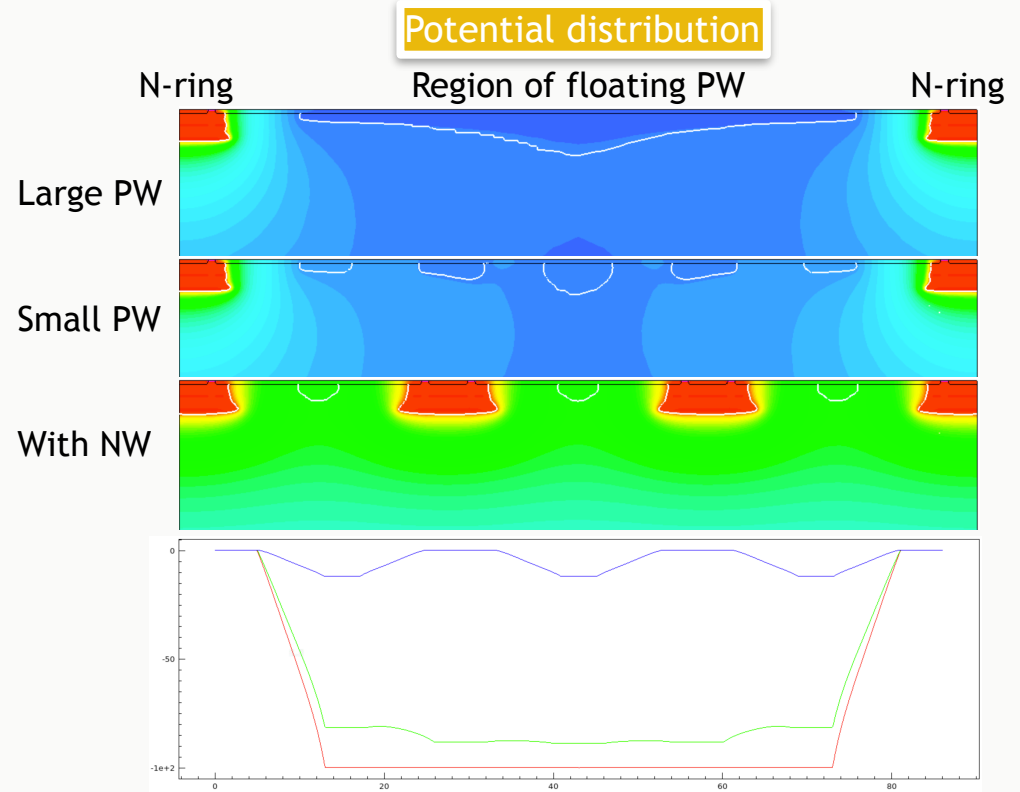
IMPLEMENT N-RING/DNW & REDUCE PW

- Both approaches are related
 - Use n-ring (with a fixed potential) to occupy the space of PW (floating potential)
- N-ring:
 - Encloses the pixel matrix -> shape the field of edge pixels & collect the leakage outside the matrix
 - Encloses isolated structures which requires a similar potential at the p-stop/ring (like the test structures)
 - Connect all the n-ring to the n-ring at the guard-ring -> build a common potential
- DNW:
 - If structures can be put into a common DNW (connected to the N-ring), the potential distribution will be more ordered
 - e.g. with low voltage, for signals, etc.
 - HV related parts requires different approaches



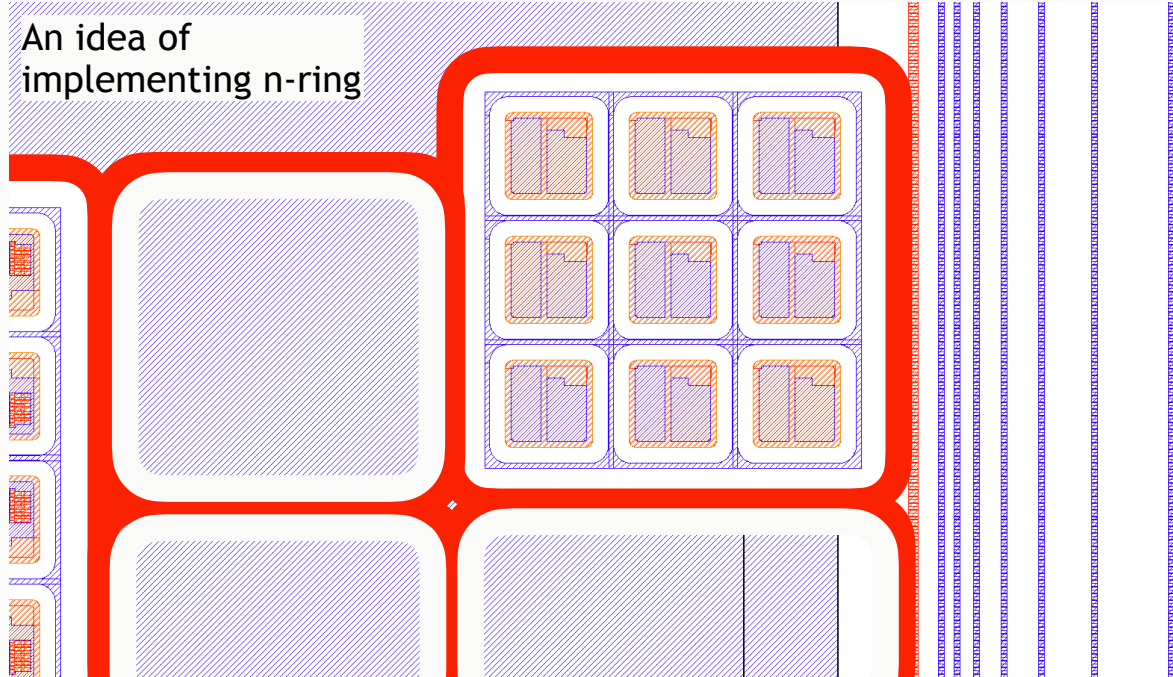
REDUCE PW & IMPLEMENT N-RING/DNW

- Enclosing the floating PW with n-ring is maybe still not enough
- Too low potential may still occur at the large PW, and can cause high E-field (triggers breakdown) or punch-through
- Very extreme case:
The PW is so large that the region beneath cannot be easily depleted
-> the PW will have the same potential as the backside
-> breakdown is merely determined by the spacing between PW and the surrounding n-ring
- Possible approaches (require more discussions):
 - Divide the PW into small parts
 - Add N-ring between small PW parts
 - Simply reduce the PW size, create large spacing
 - Add contact to PW to add voltage
 - Use DNW to hold the PW, merge DNW to N-ring



REDUCE PW & IMPLEMENT N-RING/DNW

Very preliminary and conceptional



SUMMARY

- From the inspection of the design layout, several features might affect the performance of the sensor part of the detector, if the edge biasing and floating p-stop would be adopted:
 - Sharp corners → unexpected high E-field
 - Large floating PW with an irregular shape, and the structures isolated from the pixel matrix → potential distribution hard to predict
 - Guard ring geometry still has the room for optimisation
- The effect from floating PW has been visualised using TCAD simulation
 - A large floating PW can lead to large potential drop (high field), or punch-through
 - Using n-ring with fixed potential to divide the PW can provide a better potential distribution
- Possible measures:
 - Round sharp corners
 - Re-organise isolated structures → build a more ordered layout
 - Use n-ring with a fixed voltage to enclose structures and divide the PW → may help to reduce the effect of large PW
 - Use common DNW to contain some of the structures can also help to regulate the potential distribution
 - Implement a guard ring structure based on the previous knowledge